



New Frontiers in Optical Coordinate Measuring Systems

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submissions:
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Message from the Guest Editors

Dear Colleagues,

Coordinate measuring systems offer high accuracy, automation of measurements and universality, which translates into shortening of the measurement time, which is one of the most sought aspects of measurements in the Industry 4.0 era. The trend observed in recent years clearly indicates that systems of this type, additionally operating in connection with automation systems and devices such as industrial robots, will be one of the most popular tools, in the future, for quality assessment in advanced production processes. We invite contributions to this Special Issue on topics including, but not limited to, the following areas:

Optical CMM;

Multisensor CMM;

Optical metrology in manufacturing;

CCD/CMOS sensors;

Laser triangulation sensors;

Structured light sensors;

Vision-based measurement systems;

Fringe optics;

Optical metrology systems;

Optical solutions for in-process control;

Special Issue





applied



In-line optical inspection systems;
Automation of optical measuring systems.
Portable optical measuring systems;
Optical metrology systems in Industry 4.0;
Traceability of optical metrology systems;

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Message from the Editor-in-Chief

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